

Notice of References Cited

Application/Contr. No.:

09/823,926

Applicant(s)/Patent Under
Reexamination
CAMPARDO ET AL.

Examiner

Guy J. Lamarre, P.E.

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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	Q					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Russ et al. 'Non-intrusive built-in self-test for FPGA and MCM applications;' IEEE; page(s): 480 - 485; 8-10 Aug. 1995.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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